

FEATURES

- Up to 100 Mbps data rate (NRZ)
- Low propagation delay: 23 ns typical
- Low dynamic power consumption
- Bidirectional communication
- ▶ 3.3 V to 5 V level translation
- High temperature operation: 125°C
- High common-mode transient immunity: >25 kV/µs
- Default high output: ADuM1280/ADuM1281
- Default low output: ADuM1285/ADuM1286
- Narrow body, RoHS-compliant, 8-lead SOIC
- Safety and regulatory approvals
 - UL 1577

V_{ISO} = 3000 V_{RMS} for 1 minute

- ▶ IEC/EN/CSA 62368-1
- ▶ IEC/CSA 61010-1
- DIN EN IEC 60747-17 (VDE 0884-17)
 - ► V_{IORM} = 565 V_{PEAK}
- AEC-Q100 qualified for automotive applications

APPLICATIONS

- General-purpose multichannel isolation
- Data converter isolation
- Industrial field bus isolation
- Hybrid electric vehicles, battery monitor, and motor drive

GENERAL DESCRIPTION

The ADuM1280/ADuM1281/ADuM1285/ADuM1286¹ are dual-channel digital isolators based on the Analog Devices, Inc., iCoupler® technology. Combining high speed CMOS and monolithic air core transformer technology, these isolation components provide outstanding performance characteristics superior to alternatives, such as optocoupler devices and other integrated couplers.

With propagation delay at 23 ns, pulse width distortion is less than 2 ns for C grade. Channel-to-channel matching is tight at 5 ns for C grade. The two channels of the ADuM1280/ADuM1281/ADuM1285/ADuM1286 are independent isolation channels and are available in two channel configurations with three different data rates up to 100 Mbps (see the Ordering Guide). Industrial grade models operate with the supply voltage on either side ranging from 3.135 V to 5.5 V and the automotive grades operate from 3.135 V to 5.5 V, providing compatibility with lower voltage systems as well as enabling a voltage translation functionality across the isolation barrier. Unlike other optocoupler alternatives, the ADuM1280/AD-

¹ Protected by U.S. Patents 5,952,849; 6,873,065; 6,903,578; and 7,075,329. Other patents are pending.

Rev. E

feature that ensures dc correctness in the absence of input logic transitions. When power is first applied or is not yet applied to the input side, the ADuM1280 and ADuM1281 have a default high output, and the ADuM1285 and ADuM1286 have a default low output. For more information on safety and regulatory approvals, go to www.analog.com/icouplersafety.

uM1281/ADuM1285/ADuM1286 isolators have a patented refresh



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3 kV RMS Dual Channel Digital Isolators

FUNCTIONAL BLOCK DIAGRAMS





Figure 2. ADuM1281/ADuM1286

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REVISION HISTORY

5/2025—Rev. D to Rev. E

Changes to Features Section	1
Changes to Regulatory Information Section and Table 14	8
Changes to Table 15	9
Changed DIN V VDE V 0884-10 (VDE V 0884-10): 2006-12 Insulation Characteristics Section to DIN	
EN IEC 60747-17 (VDE 0884-17) Insulation Characteristics Section	9
Changes to DIN V VDE V 0884-10 (VDE V 0884-10): 2006-12 Insulation Characteristics Section, Table	
16, and Figure 3 Caption	9
Changes to Table 19.	. 11
Changes to Insulation Lifetime Section	16
Deleted Figure 15 to Figure 17; Renumbered Sequentially	16
Added Number of Inputs, Maximum Data Rate, Maximum Propagation Delay, and Output Default State	
Options	18
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ELECTRICAL CHARACTERISTICS—5 V OPERATION

All typical specifications are at $T_A = 25^{\circ}$ C, $V_{DD1} = V_{DD2} = 5$ V. Minimum/maximum specifications apply over the entire recommended operation range: $4.5 \text{ V} \le V_{DD1} \le 5.5 \text{ V}$, $4.5 \text{ V} \le V_{DD2} \le 5.5 \text{ V}$, -40° C $\le T_A \le 125^{\circ}$ C, unless otherwise noted. Switching specifications are tested with $C_L = 15$ pF and CMOS signal levels, unless otherwise noted.

Table 1.

		Α	, WA Gra	ades	E	8, WB Gr	ades	C	, WC Gr	ades	_	
Parameter	Symbol	Min	Тур	Мах	Min	Тур	Мах	Min	Тур	Max	Unit	Test Conditions
SWITCHING SPECIFICATIONS												
Pulse Width	PW	1000			40			10			ns	Within PWD limit
Data Rate				1			25			100	Mbps	Within PWD limit
Propagation Delay	t _{PHL} , t _{PLH}			50			35	20	23	29	ns	50% input to 50% output
Pulse Width Distortion	PWD			10			3			2	ns	t _{PLH} – t _{PHL}
Change vs. Temperature			7			3			1.5		ps/°C	
Propagation Delay Skew	t _{PSK}			38			12			9	ns	Between any two units at same operating conditions
Channel Matching ¹												
Codirectional	t _{PSKCD}			5			3			2	ns	
Opposing-Direction	t _{PSKOD}			10			6			5	ns	
Jitter			2			2			1		ns	

¹ Codirectional channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on the same side of the isolation barrier. Opposing-direction channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on opposing sides of the isolation barrier.

Table 2.

		1 Mbps—A, B, C, WA, WB, WC Grades			25 Mbps—B, C, WB, WC Grades			100 Mbps—C, WC Grades				
Parameter	Symbol	Min	Тур	Max	Min	Тур	Мах	Min	Тур	Max	Unit	Test Conditions
SUPPLY CURRENT												No load
ADuM1280/ADuM1285	I _{DD1}		1.1	1.6		6.2	7.0		20	25	mA	
	I _{DD2}		2.7	4.5		4.8	7.0		9.5	15	mA	
ADuM1281/ADuM1286	I _{DD1}		2.1	2.6		4.9	6.0		15	19	mA	
	I _{DD2}		2.3	2.9		4.7	6.4		15.6	19	mA	

Table 3. For All Models

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions
DC SPECIFICATIONS						
Logic High Input Threshold	V _{IH}	0.7 V _{DDx}			V	
Logic Low Input Threshold	VIL			0.3 V _{DDx}	V	
Logic High Output Voltages	V _{OH}	V _{DDx} - 0.1	5.0		V	I _{Ox} = −20 µA, V _{Ix} = V _{IxH}
		V _{DDx} - 0.4	4.8		V	$I_{Ox} = -3.2 \text{ mA}, V_{Ix} = V_{IxH}$
Logic Low Output Voltages	V _{OL}		0.0	0.1	V	I_{Ox} = 20 μ A, V_{Ix} = V_{IxL}
			0.2	0.4	V	I _{Ox} = 3.2 mA, V _{Ix} = V _{IxL}
Input Current per Channel	li li	-10	+0.01	+10	μA	$0 V \le V_{lx} \le V_{DDx}$
Supply Current per Channel						
Quiescent Input Supply Current	I _{DDI(Q)}		0.54	0.8	mA	
Quiescent Output Supply Current	I _{DDO(Q)}		1.6	2.0	mA	
Dynamic Input Supply Current	I _{DDI(D)}		0.09		mA/Mbps	
Dynamic Output Supply Current	I _{DDO(D)}		0.04		mA/Mbps	

Table 3. For All Models (Continued)

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions
Undervoltage Lockout						
Positive V _{DDx} Threshold	V _{DDXUV+}		2.75		V	
Negative V _{DDx} Threshold	V _{DDXUV} -		2.65		V	
V _{DDx} Hysteresis	V _{DDXUVH}		0.1		V	
AC SPECIFICATIONS						
Output Rise/Fall Time	t _R /t _F		2.5		ns	10% to 90%
Common-Mode Transient Immunity ¹	CM	25	35		kV/μs	$V_{lx} = V_{DDx}$, $V_{CM} = 1000$ V, transient magnitude = 800 V
Refresh Period	t _r		1.6		μs	

1 |CM| is the maximum common-mode voltage slew rate that can be sustained while maintaining V_o > 0.8 V_{DDx}. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

ELECTRICAL CHARACTERISTICS—3.3 V OPERATION

All typical specifications are at $T_A = 25^{\circ}$ C, $V_{DD1} = V_{DD2} = 3.3$ V. Minimum/maximum specifications apply over the entire recommended operation range: $3.135 \text{ V} \le V_{DD1} \le 3.6 \text{ V}$, $3.135 \text{ V} \le V_{DD2} \le 3.6 \text{ V}$, -40° C $\le T_A \le 125^{\circ}$ C, unless otherwise noted. Switching specifications are tested with $C_L = 15 \text{ pF}$ and CMOS signal levels, unless otherwise noted.

Table 4.												
		A, WA Grades			B, WB Grades			C, WC Grades				
Parameter	Symbol	Min	Тур	Max	Min	Тур	Мах	Min	Тур	Мах	Unit	Test Conditions
SWITCHING SPECIFICATIONS												
Pulse Width	PW	1000			40			10			ns	Within PWD limit
Data Rate				1			25			100	Mbps	Within PWD limit
Propagation Delay	t _{PHL} , t _{PLH}			50			35	22	27	35	ns	50% input to 50% output
Pulse Width Distortion	PWD			10			3			2.5	ns	t _{PLH} - t _{PHL}
Change vs. Temperature			7			3			1.5		ps/°C	
Propagation Delay Skew	t _{PSK}			38			16			12	ns	Between any two units at same operating conditions
Channel Matching ¹												
Codirectional	t _{PSKCD}			5			3			2.5	ns	
Opposing-Direction	t _{PSKOD}			10			6			5	ns	
Jitter			2			2			1		ns	

¹ Codirectional channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on the same side of the isolation barrier. Opposing-direction channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on opposing sides of the isolation barrier.

		1 Mbps—A, B, C, WA, WB, WC Grades			25 Mbps—B, C, WB, WC Grades			100 Mbps—C, WC Grades				
Parameter	Symbol	Min	Тур	Мах	Min	Тур	Мах	Min	Тур	Мах	Unit	Test Conditions
SUPPLY CURRENT												No load
ADuM1280/ADuM1285	I _{DD1}		0.75	1.4		5.1	9.0		17	23	mA	
	I _{DD2}		2.0	3.5		2.7	4.6		4.8	9	mA	
ADuM1281/ADuM1286	I _{DD1}		1.6	2.1		3.8	5.0		11	15	mA	
	I _{DD2}		1.7	2.3		3.9	6.2		11	15	mA	

Table 6. For All Models

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions
DC SPECIFICATIONS						
Logic High Input Threshold	V _{IH}	0.7 V _{DDx}			V	
Logic Low Input Threshold	VIL			0.3 V _{DDx}	V	
Logic High Output Voltages	V _{OH}	V _{DDx} - 0.1	3.0		V	$I_{Ox} = -20 \ \mu A, \ V_{Ix} = V_{IxH}$
		V _{DDx} - 0.4	2.8		V	$I_{Ox} = -3.2 \text{ mA}, V_{Ix} = V_{IxH}$
Logic Low Output Voltages	V _{OL}		0.0	0.1	V	$I_{Ox} = 20 \ \mu A, \ V_{Ix} = V_{IxL}$
			0.2	0.4	V	I_{Ox} = 3.2 mA, V_{Ix} = V_{IxL}
Input Current per Channel	lı lı	-10	+0.01	+10	μA	$0 V \le V_{Ix} \le V_{DDx}$
Supply Current per Channel						
Quiescent Input Supply Current	I _{DDI(Q)}		0.4	0.6	mA	
Quiescent Output Supply Current	I _{DDO(Q)}		1.2	1.7	mA	
Dynamic Input Supply Current	I _{DDI(D)}		0.08		mA/Mbps	
Dynamic Output Supply Current	I _{DDO(D)}		0.015		mA/Mbps	
Undervoltage Lockout						
Positive V _{DDx} Threshold	V _{DDxUV+}		2.75		V	
Negative V _{DDx} Threshold	V _{DDxUV} -		2.65		V	
V _{DDX} Hysteresis	V _{DDxUVH}		0.1		V	
AC SPECIFICATIONS						
Output Rise/Fall Time	t _R /t _F		3		ns	10% to 90%
Common-Mode Transient Immunity ¹	CM	25	35		kV/μs	$V_{1x} = V_{DDx}$, $V_{CM} = 1000$ V, transient magnitude = 800 V
Refresh Period	t _r		1.6		μs	

¹ |CM| is the maximum common-mode voltage slew rate that can be sustained while maintaining V_o > 0.8 V_{DDX}. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

ELECTRICAL CHARACTERISTICS—MIXED 5 V/3.3 V OPERATION

All typical specifications are at $T_A = 25^{\circ}$ C, $V_{DD1} = 5$ V, $V_{DD2} = 3.3$ V. Minimum/maximum specifications apply over the entire recommended operation range: $4.5 \text{ V} \le V_{DD1} \le 5.5 \text{ V}$, $3.135 \text{ V} \le V_{DD2} \le 3.6 \text{ V}$; and -40° C $\le T_A \le 125^{\circ}$ C, unless otherwise noted. Switching specifications are tested with $C_L = 15 \text{ pF}$ and CMOS signal levels unless otherwise noted.

Table 7.

		А	, WA Gra	ades	В	, WB Gr	ades	C	, WC Gr	ades		
Parameter	Symbol	Min	Тур	Мах	Min	Тур	Мах	Min	Тур	Мах	Unit	Test Conditions
SWITCHING SPECIFICATIONS												
Pulse Width	PW	1000			40			10			ns	Within PWD limit
Data Rate				1			25			100	Mbps	Within PWD limit
Propagation Delay	t _{PHL} , t _{PLH}			50			35	20	25	31	ns	50% input to 50% output
Pulse Width Distortion	PWD			10			3			2	ns	t _{PLH} - t _{PHL}
Change vs. Temperature			7			3			1.5		ps/°C	
Propagation Delay Skew	t _{PSK}			38			16			12	ns	Between any two units at same operating conditions
Channel Matching ¹												
Codirectional	t _{PSKCD}			5			3			2	ns	
Opposing-Direction	t _{PSKOD}			10			6			5	ns	
Jitter			2			2			1		ns	

¹ Codirectional channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on the same side of the isolation barrier. Opposing-direction channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on opposing sides of the isolation barrier.

Table 8.

		1 Mbp	1 Mbps—A, B, C, WA, WB, WC Grades			25 Mbps—B, C, WB, WC Grades			0 Mbps– Grade	-		
Parameter	Symbol	Min	Тур	Max	Min	Тур	Max	Min	Тур	Мах	Unit	Test Conditions
SUPPLY CURRENT												No load
ADuM1280/ADuM1285	I _{DD1}		1.1	1.6		6.2	7.0		20	25	mA	
	I _{DD2}		2.0	3.5		2.7	4.6		4.8	9.0	mA	
ADuM1281/ADuM1286	I _{DD1}		2.1	2.6		4.9	6.0		15	19	mA	
	I _{DD2}		1.7	2.3		3.9	6.2		11	15	mA	

Table 9. For All Models

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions
DC SPECIFICATIONS						
Logic High Input Threshold	VIH	0.7 V _{DDx}			V	
Logic Low Input Threshold	V _{IL}			0.3 V _{DDx}	V	
Logic High Output Voltages	V _{OH}	V _{DDx} - 0.1	V _{DDx}		V	$I_{Ox} = -20 \ \mu A$, $V_{Ix} = V_{IxH}$
		V _{DDx} - 0.4	V _{DDx} - 0.2		V	$I_{Ox} = -3.2 \text{ mA}, V_{Ix} = V_{IxH}$
Logic Low Output Voltages	V _{OL}		0.0	0.1	V	I_{Ox} = 20 μ A, V_{Ix} = V_{IxL}
			0.2	0.4	V	$I_{Ox} = 3.2 \text{ mA}, V_{Ix} = V_{IxL}$
Input Current per Channel	II.	-10	+0.01	+10	μA	$0 V \le V_{lx} \le V_{DDx}$
Supply Current per Channel						
Quiescent Input Supply Current	I _{DDI(Q)}		0.54	0.75	mA	
Quiescent Output Supply Current	I _{DDO(Q)}		1.2	2.0	mA	
Dynamic Input Supply Current	I _{DDI(D)}		0.09		mA/Mbps	
Dynamic Output Supply Current	I _{DDO(D)}		0.02		mA/Mbps	
Undervoltage Lockout						
Positive V _{DDX} Threshold	V _{DDxUV+}		2.75		V	
Negative V _{DDX} Threshold	V _{DDxUV} -		2.65		V	
V _{DDX} Hysteresis	V _{DDxUVH}		0.1		V	
AC SPECIFICATIONS						
Output Rise/Fall Time	t _R /t _F		2.5		ns	10% to 90%
Common-Mode Transient Immunity ¹	CM	25	35		kV/μs	$V_{lx} = V_{DDx}$, $V_{CM} = 1000$ V, transient magnitude = 800 V
Refresh Period	t _r		1.6		μs	

¹ |CM| is the maximum common-mode voltage slew rate that can be sustained while maintaining V_o > 0.8 V_{DDX}. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

ELECTRICAL CHARACTERISTICS—MIXED 3.3 V/5 V OPERATION

All typical specifications are at $T_A = 25^{\circ}$ C, $V_{DD1} = 3.3$ V, $V_{DD2} = 5$ V. Minimum/maximum specifications apply over the entire recommended operation range: 3.135 V $\leq V_{DD1} \leq 3.6$ V, 4.5 V $\leq V_{DD2} \leq 5.5$ V; and -40° C $\leq T_A \leq 125^{\circ}$ C; unless otherwise noted. Switching specifications are tested with $C_L = 15$ pF and CMOS signal levels, unless otherwise noted.

Table 10.

		Α	, WA Gra	ades	B	, WB Gr	ades	C	C, WC Gr	ades		
Parameter Symbol	Symbol	Min	Тур	Мах	Min	Тур	Мах	Min	Тур	Мах	Unit	Test Conditions
SWITCHING SPECIFICATIONS												
Pulse Width	PW	1000			40			10			ns	Within PWD limit
Data Rate				1			25			100	Mbps	Within PWD limit
Propagation Delay	t _{PHL} , t _{PLH}			50			35	20	27	33	ns	50% input to 50% output
Pulse Width Distortion	PWD			10			3			2.5	ns	t _{PLH} – t _{PHL}
Change vs. Temperature			7			3			1.5		ps/°C	
Propagation Delay Skew	t _{PSK}			38			16			12	ns	Between any two units at same operating conditions
Channel Matching ¹												
Codirectional	t _{PSKCD}			5			3			2.5	ns	
Opposing-Direction	t _{PSKOD}			10			6			5	ns	
Jitter			2			2			1		ns	

¹ Codirectional channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on the same side of the isolation barrier. Opposing-direction channel matching is the absolute value of the difference in propagation delays between any two channels with inputs on opposing sides of the isolation barrier.

Table 11.

		1 Mbp	s—A, B, (WC Gra	C, WA, WB, des	25 Mb	ops—B, C Grade	s, WB, WC s	10	0 Mbps— Grade			
Parameter	Symbol	Min	Тур	Мах	Min	Тур	Мах	Min	Тур	Мах	Unit	Test Conditions
SUPPLY CURRENT												No load
ADuM1280/ADuM1285	I _{DD1}		0.75	1.4		5.1	9.0		17	23	mA	
	I _{DD2}		2.7	4.5		4.8	7.0		9.5	15	mA	
ADuM1281/ADuM1286	I _{DD1}		1.6	2.1		3.8	5.0		11	15	mA	
	I _{DD2}		1.7	2.3		3.9	6.2		11	15	mA	

Table 12. For All Models

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions
DC SPECIFICATIONS						
Logic High Input Threshold	VIH	0.7 V _{DDx}			V	
Logic Low Input Threshold	VIL			$0.3 V_{DDx}$	V	
Logic High Output Voltages	V _{OH}	V _{DDx} - 0.1	V _{DDx}		V	$I_{Ox} = -20 \ \mu A$, $V_{Ix} = V_{IxH}$
		V _{DDx} - 0.4	V _{DDx} - 0.2		V	$I_{Ox} = -3.2 \text{ mA}, V_{Ix} = V_{IxH}$
Logic Low Output Voltages	V _{OL}		0.0	0.1	V	I_{Ox} = 20 μ A, V_{Ix} = V_{IxL}
			0.2	0.4	V	I_{Ox} = 3.2 mA, V_{Ix} = V_{IxL}
Input Current per Channel	l _l	-10	+0.01	+10	μA	$0 V \le V_{Ix} \le V_{DDx}$
Supply Current per Channel						
Quiescent Input Supply Current	I _{DDI(Q)}		0.4	0.75	mA	
Quiescent Output Supply Current	I _{DDO(Q)}		1.6	2.0	mA	
Dynamic Input Supply Current	I _{DDI(D)}		0.08		mA/Mbps	
Dynamic Output Supply Current	I _{DDO(D)}		0.03		mA/Mbps	

Table 12. For All Models (Continued)

Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions
Undervoltage Lockout						
Positive V _{DDX} Threshold	V _{DDxUV+}		2.75		V	
Negative V _{DDX} Threshold	V _{DDxUV} -		2.65		V	
V _{DDX} Hysteresis	V _{DDxUVH}		0.1		V	
AC SPECIFICATIONS						
Output Rise/Fall Time	t _R /t _F		2.5		ns	10% to 90%
Common-Mode Transient Immunity ¹	CM	25	35		kV/µs	$V_{lx} = V_{DDx}$, $V_{CM} = 1000$ V, transient magnitude = 800 V
Refresh Period	t _r		1.6		μs	

¹ |CM| is the maximum common-mode voltage slew rate that can be sustained while maintaining V_o > 0.8 V_{DDX}. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

PACKAGE CHARACTERISTICS

Table 13.						
Parameter	Symbol	Min	Тур	Max	Unit	Test Conditions/Comments
Resistance (Input-to-Output) ¹	R _{I-O}		10 ¹³		Ω	
Capacitance (Input-to-Output) ¹	CI-O		2		pF	f = 1 MHz
Input Capacitance ²	CI		4.0		pF	
IC Junction-to-Ambient Thermal Resistance	θ_{JA}		85		°C/W	Thermocouple located at center of package underside

¹ The device is considered a 2-terminal device; Pin 1 through Pin 4 are shorted together and Pin 5 through Pin 8 are shorted together.

² Input capacitance is from any input data pin to ground.

REGULATORY INFORMATION

The ADuM1280/ADuM1281/ADuM1285/ADuM1286 certification approvals are listed in Table 14. See Table 18 and Table 19 for recommended maximum working voltages for specific cross-isolation waveforms and insulation levels.

Table 14.		
UL	CSA	VDE
UL 1577 ¹	IEC/EN/CSA 62368-1	DIN EN IEC 60747-17 (VDE 0884-17) ²
Single Protection, 3000 V _{RMS}	Basic insulation, 400 V _{RMS}	Reinforced insulation, 565 V _{PEAK}
	Reinforced insulation, 200 V _{RMS}	
	IEC/CSA 61010-1	
	Basic insulation, 300 V _{RMS} , Overvoltage Category III	
	Basic insulation, 150 V _{RMS} , Overvoltage Category IV	
File E214100	File No. 205078	Certificate No. 40011599

¹ In accordance with UL 1577, each ADuM1280/ADuM1281/ADuM1285/ADuM1286 is proof tested by applying an insulation test voltage ≥ 3600 V_{RMS} for 1 second (current leakage detection limit = 6 μA).

² In accordance with DIN EN IEC 60747-17 (VDE 0884-17), each ADuM1280/ADuM1281/ADuM1285/ADuM1286 is proof tested by applying an insulation test voltage ≥ 1050 V_{PEAK} for 1 second (partial discharge detection limit = 5 pC). The asterisk (*) marked on the component designates DIN EN IEC 60747-17 (VDE 0884-17) approval.

INSULATION AND SAFETY-RELATED SPECIFICATIONS

Table	15.
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Parameter	Symbol	Value	Unit	Test Conditions/Comments
Rated Dielectric Insulation Voltage		3000	V _{RMS}	1-minute duration
Minimum External Air Gap (Clearance) ^{1, 2}	L(I01)	4.0	mm	Measured from input terminals to output terminals, shortest distance through air
Minimum External Tracking (Creepage) ¹	L(102)	4.0	mm	Measured from input terminals to output terminals, shortest distance path along body
Minimum Internal Gap (Internal Clearance)		18	μm	Insulation distance through insulation
Tracking Resistance (Comparative Tracking Index) ³	CTI	>400	V	DIN IEC 112/VDE 0303 Part 1
Material Group		П		Material Group (DIN VDE 0110, 1/89, Table 1)

¹ In accordance with IEC 62368-1/IEC 60601-1 guidelines for the measurement of creepage and clearance distances for a pollution degree of 2 and altitudes <2000 m.

² Consideration must be given to pad layout to ensure the minimum required distance for clearance is maintained.

³ CTI rating for the ADuM1280/ADuM1281/ADuM1285/ADuM1286 is >400 V and a Material Group II isolation group.

DIN EN IEC 60747-17 (VDE 0884-17) INSULATION CHARACTERISTICS

These isolators are suitable for reinforced electrical isolation within the safety limit data only. Maintenance of the safety data is ensured by protective circuits. The asterisk (*) marked on packages denotes DIN EN IEC 60747-17 (VDE 0884-17) approval.

Description	Test Conditions/Comments	Symbol	Characteristic	Unit
Installation Classification per DIN VDE 0110				
For Rated Mains Voltage ≤ 150 V _{RMS}			I to IV	
For Rated Mains Voltage ≤ 300 V _{RMS}			I to III	
For Rated Mains Voltage ≤ 400 V _{RMS}			I to II	
Climatic Classification			40/105/21	
Pollution Degree per DIN VDE 0110, Table 1			2	
Maximum Repetitive Isolation Voltage		VIORM	565	VPEAK
Maximum Working Insulation Voltage		VIOWM	400	V _{RMS}
Input-to-Output Test Voltage, Method B1	$V_{IORM} \times 1.875 = V_{pd(m)}$, 100% production test, $t_{ini} = t_m = 1$ sec, partial discharge < 5 pC	V _{pd(m)}	1059	V _{PEAK}
nput-to-Output Test Voltage, Method A				
After Environmental Tests Subgroup 1	V_{IORM} × 1.6 = $V_{\text{pd}(m)}, t_{\text{ini}}$ =60 sec, t_m = 10 sec, partial discharge < 5 pC	V _{pd(m)}	904	V _{PEAK}
After Input and/or Safety Test Subgroup 2and Subgroup 3	V_{IORM} × 1.2 = $V_{\text{pd}(m)},$ t_{ini} = 60 sec, t_m = 10 sec, partial discharge < 5 pC	V _{pd(m)}	678	V _{PEAK}
Maximum Transient Isolation Voltage	V _{TEST} = 1.2 × V _{IOTM} , t = 1 sec (100% production)	V _{IOTM}	4000	V _{PEAK}
Maximum Impulse Voltage	Surge voltage in air, waveform per IEC 61000-4-5	VIMP	4000	VPEAK
Maximum Surge Isolation Voltage	$V_{TEST} \ge 1.3 \times V_{IMP}$ (sample test), tested in oil, waveform per IEC 61000-4-5	V _{IOSM}	10000	V _{PEAK}
Withstand Isolation Voltage	1 minute withstand rating	VISO	3000	V _{RMS}
Safety Limiting Values	Maximum value allowed in the event of a failure (see Figure 3)			
Case Temperature		T _S	150	°C
Total I _{DD1} and I _{DD2} Safety Limiting Current		Is	290	mA
Insulation Resistance at T _S	V _{IO} = 500 V	Rs	>10 ⁹	Ω



Figure 3. Thermal Derating Curve at V_{DDx} = 5 V, Dependence of Safety-Limiting Values with Case Temperature per DIN EN IEC 60747-17 (VDE 0884-17)

RECOMMENDED OPERATING CONDITIONS

Table 17.				
Parameter	Symbol	Min	Max	Unit
Operating Temperature	T _A	-40	+125	°C
Supply Voltages ¹	V _{DD1} , V _{DD2}			
A, B, and C Grades		3.135	5.5	V
WA, WB, and WC Grades		3.135	5.5	V
Input Signal Rise and Fall Times			1.0	ms

¹ See the DC Correctness and Magnetic Field Immunity section.

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25^{\circ}C$, unless otherwise noted.

Table 18.

10010-101					
Parameter	Rating				
Storage Temperature (T _{ST}) Range	-65°C to +150°C				
Ambient Operating Temperature (T _A) Range	-40°C to +125°C				
Supply Voltages (V _{DD1} , V _{DD2})	-0.5 V to +7.0 V				
Input Voltages (V _{IA} , V _{IB})	-0.5 V to V _{DDI} + 0.5 V				
Output Voltages (V _{OA} , V _{OB})	-0.5 V to V _{DD2} + 0.5 V				
Average Output Current per Pin ¹					
Side 1 (I _{O1})	-10 mA to +10 mA				
Side 2 (I _{O2})	-10 mA to +10 mA				
Common-Mode Transients ²	−100 kV/µs to +100 kV/µs				

See Figure 3 for maximum rated current values for various temperatures.

² Refers to common-mode transients across the insulation barrier. Commonmode transients exceeding the absolute maximum ratings may cause latch-up or permanent damage.

MAXIMUM CONTINUOUS WORKING VOLTAGE

Tabla 40 Mariana Oradia

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

able 19. Maximum Continuous Working Voltage'						
Parameter	Max	Unit	Constraint			
AC Voltage						
Bipolar Waveform	565	V _{PEAK}	Reinforced insulation rating per IEC 60747-17 (VDE 0884-17).			

¹ Refers to continuous voltage magnitude imposed across the isolation barrier. See the Insulation Lifetime section for more details.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



Figure 4. ADuM1280/ADuM1285 Pin Configuration

Table 20. ADuM1280/ADuM1285 Pin Function Descriptions

Mnemonic	Description
V _{DD1}	Supply Voltage for Isolator Side 1 (3.135 V to 5.5 V).
VIA	Logic Input A.
V _{IB}	Logic Input B.
GND ₁	Ground 1. Ground reference for Isolator Side 1.
GND ₂	Ground 2. Ground reference for Isolator Side 2.
V _{OB}	Logic Output B.
V _{OA}	Logic Output A.
V _{DD2}	Supply Voltage for Isolator Side 2 (3.135 V to 5.5 V).
	$V_{DD1} \\ V_{IA} \\ V_{IB} \\ GND_1 \\ GND_2 \\ V_{OB} \\ V_{OA}$



Figure 5. ADuM1281/ADuM1286 Pin Configuration

Table 21. ADuM1281/ADuM1286 Pin Function Descriptions

Pin No.	Mnemonic	Description
1	V _{DD1}	Supply Voltage for Isolator Side 1 (3.135 V to 5.5 V).
2	V _{OA}	Logic Output A.
3	V _{IB}	Logic Input B.
4	GND ₁	Ground 1. Ground reference for Isolator Side 1.
5	GND ₂	Ground 2. Ground reference for Isolator Side 2.
6	V _{OB}	Logic Output B.
7	VIA	Logic Input A.
8	V _{DD2}	Supply Voltage for Isolator Side 2 (3.135 V to 5.5 V).

For specific layout guidelines, refer to the AN-1109 Application Note, *Recommendations for Control of Radiated Emissions with iCoupler Devices*.

Table 22. ADuM1280 Truth Table (Positive Logic)

V _{IA} Input	V _{IB} Input	V _{DD1} State	V _{DD2} State	V _{OA} Output	V _{OB} Output	Notes
Н	Н	Powered	Powered	Н	Н	
L	L	Powered	Powered	L	L	
Н	L	Powered	Powered	Н	L	
L	Н	Powered	Powered	L	н	
L	L	Unpowered	Powered	Н	H	Outputs return to the input state within 1.6 μs of V_{DDI} power restoration.
Х	Х	Powered	Unpowered	Indeterminate	Indeterminate	Outputs return to the input state within 1.6 μs of V_{DDO} power restoration.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

V _{IA} Input	V _{IB} Input	V _{DD1} State	V _{DD2} State	V _{OA} Output	V _{OB} Output	Notes
Н	Н	Powered	Powered	Н	Н	
L	L	Powered	Powered	L	L	
Н	L	Powered	Powered	Н	L	
L	Н	Powered	Powered	L	Н	
Х	L	Unpowered	Powered	Indeterminate	Н	Outputs return to the input state within 1.6 μs of V_{DD1} power restoration.
L	X	Powered	Unpowered	Н	Indeterminate	Outputs return to the input state within 1.6 μs of V_{DDO} power restoration.

Table 23. ADuM1281 Truth Table (Positive Logic)

Table 24. ADuM1285 Truth Table (Positive Logic)

V _{IA} Input	V _{IB} Input	V _{DD1} State	V _{DD2} State	V _{OA} Output	V _{OB} Output	Notes
Н	Н	Powered	Powered	Н	Н	
L	L	Powered	Powered	L	L	
Н	L	Powered	Powered	Н	L	
L	Н	Powered	Powered	L	Н	
L	L	Unpowered	Powered	L	L	Outputs return to the input state within 1.6 μs of V_{DDI} power restoration.
Х	X	Powered	Unpowered	Indeterminate	Indeterminate	Outputs return to the input state within 1.6 μs of V_{DDO} power restoration.

Table 25. ADuM1286 Truth Table (Positive Logic)

V _{IA} Input	V _{IB} Input	V _{DD1} State	V _{DD2} State	V _{OA} Output	V _{OB} Output	Notes
Н	Н	Powered	Powered	Н	Н	
L	L	Powered	Powered	L	L	
Н	L	Powered	Powered	Н	L	
L	Н	Powered	Powered	L	н	
Х	L	Unpowered	Powered	Indeterminate	L	Outputs return to the input state within 1.6 μs of V_{DD1} power restoration.
L	X	Powered	Unpowered	L	Indeterminate	Outputs return to the input state within 1.6 μs of V_{DDO} power restoration.

TYPICAL PERFORMANCE CHARACTERISTICS



Figure 6. Typical Supply Current per Input Channel vs. Data Rate for 5 V and 3.3 V Operation



Figure 7. Typical Supply Current per Output Channel vs. Data Rate for 5 V and 3.3 V Operation (No Output Load)



Figure 8. Typical Supply Current per Output Channel vs. Data Rate for 5 V and 3.3 V Operation (15 pF Output Load)



Figure 9. Typical ADuM1280 or ADuM1285 V_{DD1} Supply Current vs. Data Rate for 5 V and 3.3 V Operation



Figure 10. Typical ADuM1280 or ADuM1285 V_{DD2} Supply Current vs. Data Rate for 5 V and 3.3 V Operation



Figure 11. Typical ADuM1281 or ADuM1286 V_{DD1} or V_{DD2} Supply Current vs. Data Rate for 5 V and 3.3 V Operation

APPLICATIONS INFORMATION

PRINTED CIRCUIT BOARD LAYOUT

The ADuM1280/ADuM1281/ADuM1285/ADuM1286 digital isolator requires no external interface circuitry for the logic interfaces. Power supply bypassing is strongly recommended at both input and output supply pins V_{DD1} and V_{DD2} (see Figure 12). The capacitor value should be between 0.01 μ F and 0.1 μ F. The total lead length between both ends of the capacitor and the input power supply pin should not exceed 20 mm.

The ADuM1280/ADuM1281/ADuM1285/ADuM1286 can readily meet CISPR 22 Class A (and FCC Class A) emissions standards, as well as the more stringent CISPR 22 Class B (and FCC Class B) standards in an unshielded environment, with proper PCB design choices. Refer to the AN-1109 Applicaton Note, *Recommendations for Control of Radiated Emissions with iCoupler Devices* for PCB-related EMI mitigation techniques, including board layout and stack-up issues.

PROPAGATION DELAY-RELATED PARAMETERS

Propagation delay is a parameter that describes the time it takes a logic signal to propagate through a component. The input-to-output propagation delay time for a high-to-low transition may differ from the propagation delay time of a low-to-high transition.



Figure 12. Propagation Delay Parameters

Pulse width distortion is the maximum difference between these two propagation delay values and an indication of how accurately the timing of the input signal is preserved.

Channel-to-channel matching refers to the maximum amount the propagation delay differs between channels within a single AD-uM1280/ADuM1281/ADuM1285/ADuM1286 component.

Propagation delay skew refers to the maximum amount the propagation delay differs between multiple ADuM1280/ADuM1281/ADuM1285/ADuM1286 components operating under the same conditions.

DC CORRECTNESS AND MAGNETIC FIELD IMMUNITY

Positive and negative logic transitions at the isolator input cause narrow (~1 ns) pulses to be sent via the transformer to the decoder. The decoder is bistable and is, therefore, either set or reset by the pulses indicating input logic transitions. In the absence of logic transitions at the input for more than ~1.6 μ s, a periodic set of refresh pulses indicative of the correct input state are sent to ensure dc correctness at the output.

If the decoder receives no pulses for more than about 6.4 μ s, the input side is assumed to be unpowered or nonfunctional, in which case, the isolator output is forced to a default low state by the watchdog timer circuit.

The limitation on the device's magnetic field immunity is set by the condition in which induced voltage in the transformer receiving coil is sufficiently large to either falsely set or reset the decoder. The following analysis defines such conditions. The ADuM1280 is examined in a 3.3 V operating condition because it represents the most susceptible mode of operation of this product.

The pulses at the transformer output have an amplitude greater than 1.5 V. The decoder has a sensing threshold of about 1.0 V, therefore establishing a 0.5 V margin in which induced voltages can be tolerated. The voltage induced across the receiving coil is given by

$$V = (-d\beta/dt) \sum \pi r_n^2; n = 1, 2, ..., N$$
(1)

where:

 β is the magnetic flux density. r_n is the radius of the n^{th} turn in the receiving coil. *N* is the number of turns in the receiving coil.

Given the geometry of the receiving coil in the ADuM1280 and an imposed requirement that the induced voltage be, at most, 50% of the 0.5 V margin at the decoder, a maximum allowable magnetic field is calculated, as shown in Figure 13.



Figure 13. Maximum Allowable External Magnetic Flux Density

For example, at a magnetic field frequency of 1 MHz, the maximum allowable magnetic field of 0.08 kgauss induces a voltage of 0.25 V at the receiving coil. This is about 50% of the sensing threshold and does not cause a faulty output transition. If such an event occurs, with the worst-case polarity, during a transmitted pulse, it would reduce the received pulse from >1.0 V to 0.75 V. This is still well above the 0.5 V sensing threshold of the decoder.

The preceding magnetic flux density values correspond to specific current magnitudes at given distances away from the ADuM1280 transformers. Figure 14 expresses these allowable current mag-

APPLICATIONS INFORMATION

nitudes as a function of frequency for selected distances. The ADuM1280 is very insensitive to external fields. Only extremely large, high frequency currents, very close to the component could potentially be a concern. For the 1 MHz example noted, place a 0.2 kA current 5 mm away from the ADuM1280 to affect component operation.



Figure 14. Maximum Allowable Current for Various Current to ADuM1280 Spacings

Note that at combinations of strong magnetic field and high frequency, any loops formed by printed circuit board traces could induce sufficiently large error voltages to trigger the thresholds of succeeding circuitry. Take care to avoid PCB structures that form loops.

POWER CONSUMPTION

The supply current at a given channel of the ADuM1280/ADuM1281/ADuM1285/ADuM1286 isolator is a function of the supply voltage, the data rate of the channel, and the output load of the channel.

For each input channel, the supply current is given by

$I_{DDI} = I_{DDI(Q)}$	$f \le 0.5 f_r$
------------------------	-----------------

 $I_{DDI} = I_{DDI(D)} \times (2f - f_r) + I_{DDI(Q)} \qquad f > 0.5 f_r$

For each output channel, the supply current is given by

$$I_{DDO} = I_{DDO(Q)} \qquad \qquad f \le 0.5 f_r$$

$$I_{DDO} = (I_{DDO(D)} + (0.5 \times 10^{-3}) \times C_L \times V_{DDO}) \times (2f - f_r) + I_{DDO(Q)}$$

f > 0.5 f_r

where:

*I*_{DDI (D)}, *I*_{DDO (D)} are the input and output dynamic supply currents per channel (mA/Mbps).

 C_L is the output load capacitance (pF).

 V_{DDO} is the output supply voltage (V).

f is the input logic signal frequency (MHz); it is half the input data rate, expressed in units of Mbps.

 f_r is the input stage refresh rate (Mbps) = $1/t_r$ (µs).

 $I_{DDI (Q)}$, $I_{DDO (Q)}$ are the specified input and output quiescent supply currents (mA).

To calculate the total V_{DD1} and V_{DD2} supply current, the supply currents for each input and output channel corresponding to V_{DD1} and V_{DD2} are calculated and totaled. Figure 6 and Figure 7 show perchannel supply currents as a function of data rate for an unloaded output condition. Figure 8 shows the per-channel supply current as a function of data rate for a 15 pF output condition. Figure 9 through Figure 11 show the total V_{DD1} and V_{DD2} supply current as a function of data rate for ADuM1280/ADuM1281 channel configurations.

INSULATION LIFETIME

All insulation structures eventually break down when subjected to voltage stress over a sufficiently long period. The rate of insulation degradation is dependent on the characteristics of the voltage waveform applied across the insulation. In addition to the testing performed by the regulatory agencies, Analog Devices carries out an extensive set of evaluations to determine the lifetime of the insulation structure within the ADuM1280/ADuM1281/ADuM1285/AD-uM1286.

Analog Devices performs accelerated life testing using voltage levels higher than the rated continuous working voltage. Acceleration factors for several operating conditions are determined. These factors allow calculation of the time to failure at the actual working voltage. The values shown in Table 19 summarize the maximum continuous working voltages as per IEC 60747-17. Operation at these high working voltages can lead to shortened insulation life in some cases.

OUTLINE DIMENSIONS

Package Drawing (Option)	Package Type	Package Description
R-8	SOIC_N	8-Lead Standard Small Outline Package

For the latest package outline information and land patterns (footprints), go to Package Index.

ORDERING GUIDE

Model ^{1, 2, 3}	Temperature Range	Package Description	Packing Quantity	Package Option
ADuM1280ARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1280WARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1280BRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1280WBRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1280CRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1280WCRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1281ARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1281WARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1281BRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1281WBRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1281CRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1281WCRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1285ARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1285WARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1285BRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1285WBRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1285CRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1285WCRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1286ARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1286WARZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1286BRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1286WBRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1286CRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8
ADuM1286WCRZ	-40°C to +125°C	8-Lead SOIC_N	Tube, 98	R-8

¹ Z = RoHS Compliant Part.

² Tape and reel are available. The addition of an "-RL7" suffix designates a 7" (1,000 units) tape and reel option.

³ W = Qualified for Automotive Applications.

OUTLINE DIMENSIONS

NUMBER OF INPUTS, MAXIMUM DATA RATE, MAXIMUM PROPAGATION DELAY, AND OUTPUT DEFAULT STATE OPTIONS

Model ^{1, 2, 3}	No. of Inputs,V _{DD1} Side	No. of Inputs,V _{DD2} Side	Maximum Data Rate (Mbps)	Maximum Propagation Delay, 5 V	Output Default State
ADuM1280ARZ	2	0		50	High
ADuM1280WARZ	2	0	1	50	High
ADuM1280BRZ	2	0	25	35	High
ADum 1200BRZ ADuM1280WBRZ	2	-	25	35	
		0			High
ADuM1280CRZ	2	0	100	24	High
ADuM1280WCRZ	2	0	100	24	High
ADuM1281ARZ	1	1		50	High
ADuM1281WARZ	1	1	1	50	High
ADuM1281BRZ	1	1	25	35	High
ADuM1281WBRZ	1	1	25	35	High
ADuM1281CRZ	1	1	100	24	High
ADuM1281WCRZ	1	1	100	24	High
ADuM1285ARZ	2	0	1	50	Low
ADuM1285WARZ	2	0	1	50	Low
ADuM1285BRZ	2	0	25	35	Low
ADuM1285WBRZ	2	0	25	35	Low
ADuM1285CRZ	2	0	100	24	Low
ADuM1285WCRZ	2	0	100	24	Low
ADuM1286ARZ	1	1	1	50	Low
ADuM1286WARZ	1	1	1	50	Low
ADuM1286BRZ	1	1	25	35	Low
ADuM1286WBRZ	1	1	25	35	Low
ADuM1286CRZ	1	1	100	24	Low
ADuM1286WCRZ	1	1	100	24	Low

¹ Z = RoHS Compliant Part.

² Tape and reel are available. The addition of an "-RL7" suffix designates a 7" (1,000 units) tape and reel option.

³ W = Qualified for Automotive Applications.

AUTOMOTIVE PRODUCTS

The ADuM1280W, ADuM1281W, ADuM1285W, and ADuM1286W models are available with controlled manufacturing to support the quality and reliability requirements of automotive applications. Note that these automotive models may have specifications that differ from the commercial models; therefore, designers should review the Specifications section of this data sheet carefully. Only the automotive grade products shown are available for use in automotive applications. Contact your local Analog Devices account representative for specific product ordering information and to obtain the specific Automotive Reliability reports for these models.

